Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/930,672	SCHAAR ET AL.		
Examiner	Art Unit		
Allon Wong	2612		

SEARCHED					
Class	Subclass	Date	Examiner		
375	240	4/28/2005	AW		
375	240.2	4/28/2005	AW		
375	240.01	4/28/2005	AW		
375	240.12	4/28/2005	AW		
375	240.16	4/28/2005	AW		
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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